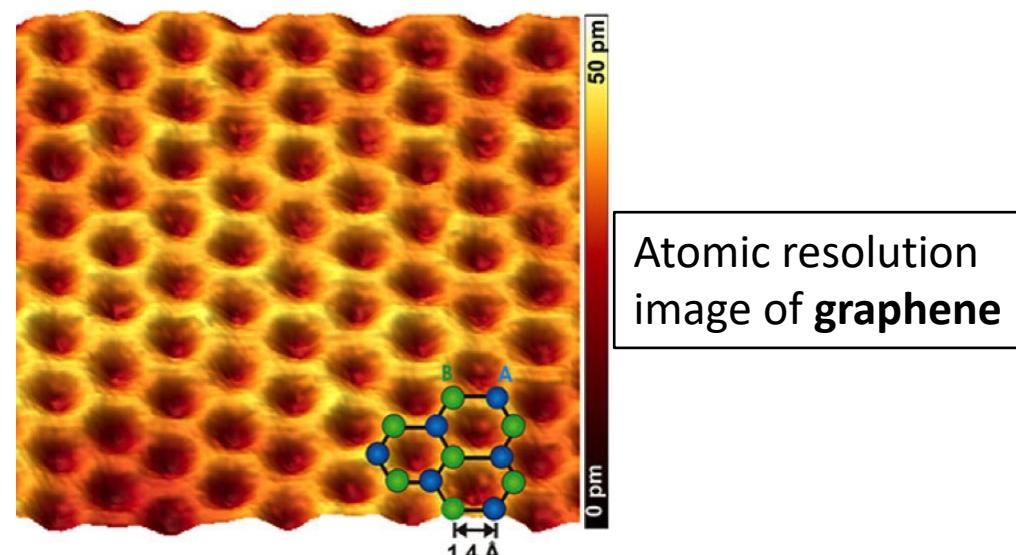
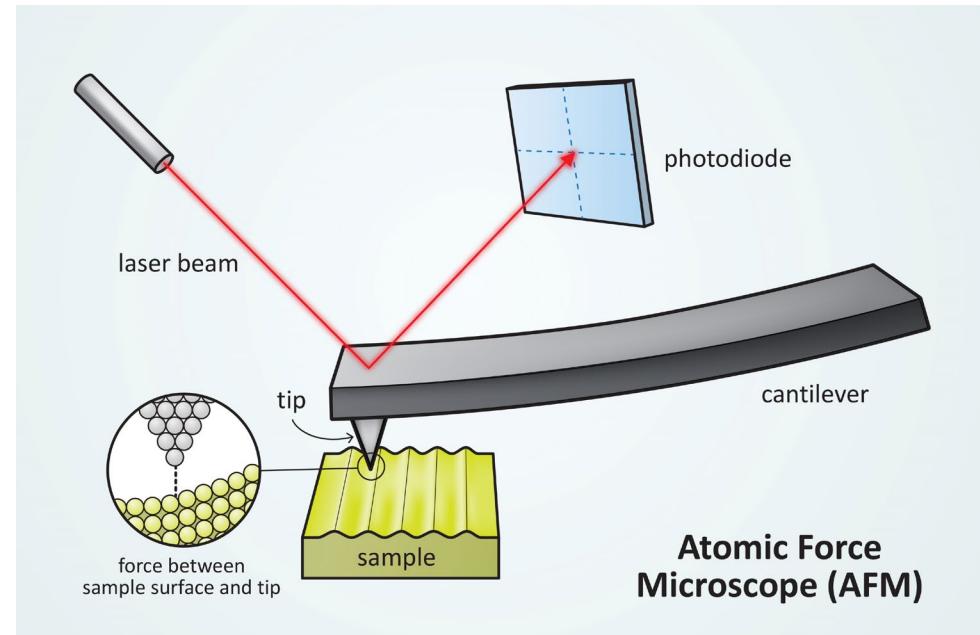
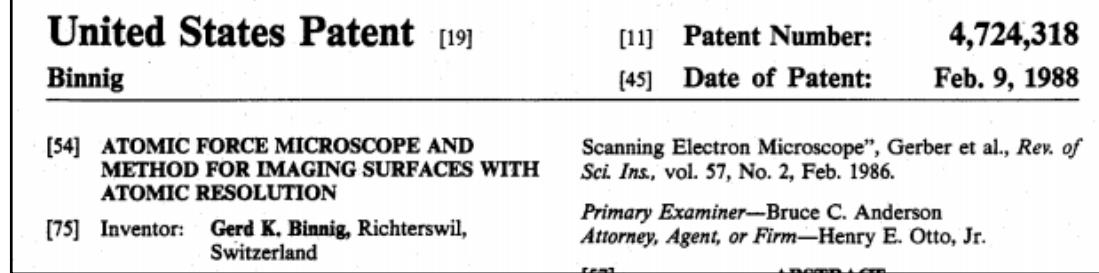
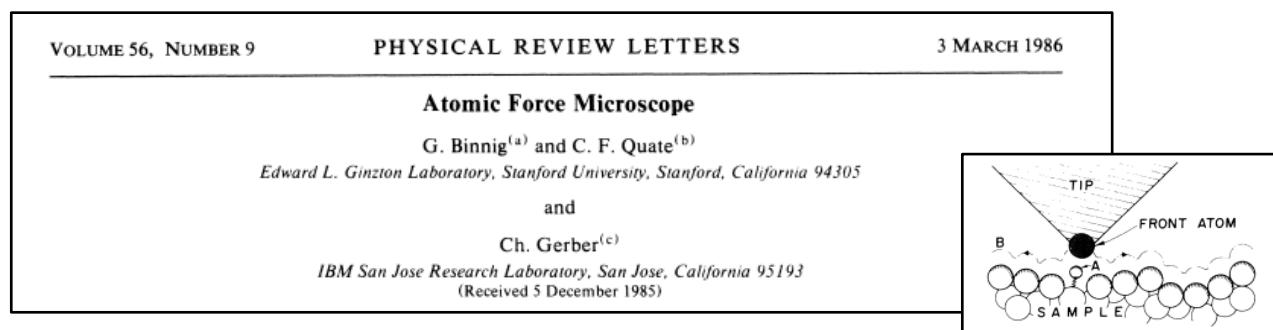


Atomic Force Microscopy (AFM)

High-resolution microscopy, based on the bending deflection of a cantilever beam.

Resolution down to fractions of nanometers (10^{-9} m)
-> of the order of the typical size of an atom ($\sim 1 \text{ \AA} = 10^{-10}$ m).

It was invented by G. Binnig (Stanford University) and C. F. Quate (IBM San Jose) and first published in **1986**.



Atomic Force Microscopy (AFM)

